SN5401, SN54LS01, SN7401, SN74LS01

QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

SDLS026

APRIL 1985 - REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

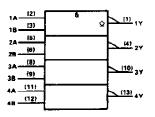
These devices contain four independent 2-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5401 and SN54LS01 are characterized for operation over the full military temperature range of -55 °C to 125 °C. The SN7401 and SN74LS01 are characterized for operation from 0 °C to 70 °C.

FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
A	В	Y
н	н	L
L	Х	н
×	L	н

logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

APRIL 1985 - REVISE
SN5401 J PACKAGE SN54LS01 J OR W PACKAGE SN7401 N PACKAGE SN74LS01 D OR N PACKAGE (TOP VIEW)
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$
SN5401 W PACKAGE (TOP VIEW)
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$
SN54LS01 FK PACKAGE (TOP VIEW)
$\begin{array}{c} 4 > 2 > 3 > 4 \\ 7 + 2 +$

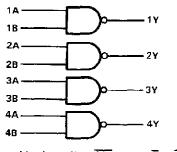
NC - No internal connection

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



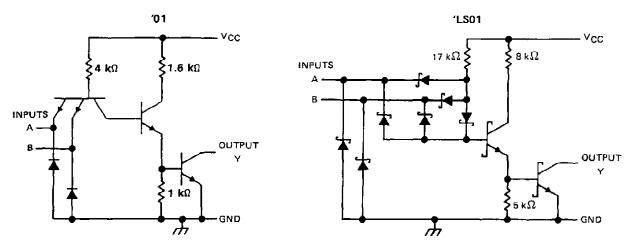
SN5401, SN54LS01. SN7401, SN74LS01 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

logic diagram (positive logic)



positive logic; Y = $\overline{A \cdot B}$ or Y = $\overline{A} + \overline{B}$

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1): '0	D1, ′LSO1	7 V
Off-state output voltage		7 V
	SN54'	
	SN74′	0°C to 70°C
Storage temperature range		5°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminals.



SN5401, SN7401 QUADRUPLE 2 INPUT POSITIVE NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

			SN5401					
		MIN	NOM	ΜΑΧ	MIN	NOM	мах	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	v
∨он	High-level output voltage			5.5			5,5	v
IOL	Low-level output current			16			16	mA
TA	Operating free-air temperature	- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	SN5401	SN7401		
PARAMETER	TEST CONDITIONS.	MIN TYP [‡] MAX	MIN TYP [‡] MAX	UNIT	
Viĸ	$V_{CC} = MIN, I = -12 mA$	- 1.5	- 1.5	v	
	$V_{CC} = MIN, V_{IL} = 0.8 V, V_{OH} = 5.5 V$		0.25	mA	
юн	VCC = MIN, VIL = 0.7 V, VOH = 5.5 V	0.25] """	
VOL	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA	0.2 0.4	0.2 0.4	V	
4	VCC = MAX, VI = 5.5 V	1	1	mΑ	
Чн	$V_{CC} = MAX, V_{I} = 2.4 V$	40	40	μA	
ΙL	$V_{CC} = MAX, V_i = 0.4 V$	-1.6	- 1.6	mА	
ССН	$V_{CC} = MAX, \forall_{ } = 0$	4 8	4 8	mΑ	
ICCL	$V_{CC} = MAX, V_{\parallel} = 4.5 V$	12 22	12 22	mA	

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. [‡]All typical values are at $V_{CC} = 5 V$, $T_A = 25 °C$.

switching characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	МАХ	UNIT
TPLH	A or B	v	RL=4kΩ,	CL = 15 pF		35	55	ns
^t PHL	7015		R _L = 400 Ω,	CL = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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SN54LS01, SN74LS01 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

		SN54LS01		SN74LS01			
	MIN	NOM	MAX	MIN	NOM	MAX	
VCC Supply voltage	4,5	5	5.5	4.75	5	5.25	V
VIH High-level input voltage	2			2			V
VIL Low-level input voltage			0.7		·····	0.8	v
VOH High-level output voltage			5.5			5.5	V
OL Low-level output current	_		4			8	mΑ
T _A Operating free-air temperature	- 55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †									
PARAMETER		IEST CONDI	TIONS	MIN	TYP‡	МАХ	MIN	TYP‡	МАХ	UNIT
VIK	V _{CC} = MIN,	lj = ~ 18 mA				- 1.5			- 1.5	V
юн	V _{CC} = MIN,	V _{IL} = MAX,	V _{OH} = 5.5 V			0.1			0.1	mΑ
14	Vcc = MIN,	V _{IH} = 2 V,	IQL = 4 mA		0.25	0.4		0.25	0.4	v
V _{OL}	Vcc = MIN,	V _{IH} ≈ 2 V,	IOL = 8 mA					0.35	0.5	ľ
4	V _{CC} = MAX,	V ₁ = 7 V				0.1	1		0.1	mA
Чн	V _{CC} = MAX,	V ₁ = 2.7 V				20	1		20	μA
ηΓ	V _{CC} = MAX,	V ₁ = 0.4 V				- 0.4			- 0.4	mA
ICCH	VCC = MAX,	VI = 0			0.8	1.6		0.8	1.6	mΑ
ICCL	V _{CC} ≠ MAX,	V ₁ = 4.5 V			2.4	4.4		2.4	4.4	mA

 \uparrow For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. \ddagger All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25° C (see note 2)

PARAMETER	FROM (INPUT)	TO {OUTPUT}	TEST CONDITIONS	MIN	TYP	МАХ	UNIT
tPLH	A or B	Y	RL=2 kΩ, CL=15 pF		17	32	nş
[‡] PHL			ng - 2 ksz, cg - 13 pr		15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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